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	Applicant(s)/Patent Under Reexamination SHIN ET AL.

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P. Kathryn Bex	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	
	Α	US-2002/0028507-A1	04-2001	Heimberg et al.	Classification
	В	US-		risinibulg et al.	435/305.3
	С	US-			
	D	US-			
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	F	US-			
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FOREIGN PATENT DOCUMENTS

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